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a metal layer forming a plurality of top contact electrodes deposited on the p-doped wide energy gap semiconductor layer having patterned regions to confine current conduction in [desired] pixels of said EL device.

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3. (once amended) The EL device of claim 1, wherein said CNC layer [are] is selected from the group of semiconductor materials consisting of Zn_xCd_{1-x}Se (core) - Zn_yMg_{1-y}Se (cladding), Zn_xCd₁. xSe (core) - Zn_zBe_{1-z}Se (cladding), Zn_xCd_{1-x}Se (core) - ZnMgSSe (cladding), In_xGa_{1-x}N (core) - GaN (cladding), GaN (core)-AlGaN (cladding), and ZnCdS (core)- ZnMgS (cladding), where the subscripts x, y, z represent molar fractions.

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5. (once amended) The EL device of claim, wherein said CNC layer is sandwiched between lattice-matched wide energy gap semiconductor layers selected from the group of semiconductors consisting of Zn_aMg_{1-a}Se, Zn_aMg_{1-a}S, Zn_aMg_{1-a}S_bSe_{1-b}, Zn_aBe_{1-a}S_bSe_{1-b},

Al_cGa_{1-c}N, and AlInN, where the subscripts a, b and c represent molar fractions.

- 6. (once amended) The EL device of claim 1, wherein said p-n junction is reverse-biased electrically to operate said device in the avalanche mode.
- 7. (once amended) The EL device of claim 1, wherein said p-n junction is forward-biased electrically to operate in injection mode.

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8. (once amended) The EL device of claim 1, wherein the layer comprising CNC further comprises multiple sub-layers of differing CNCs sandwiched between epitaxially grown thin film layers of p- and n doped wide energy gap semiconductors.

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10. (once amended) The EL device as described in claim 1, wherein said CNC layer has more than one sublayer of differing CNCs stacked to emit different colors and white light.

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- 12.(once amended) The EL device as described in claim 1, wherein more than one said CNC layers are deposited to produce red, green and blue pixel elements for a display panel.
- 44. (once amended) The EL device as described in claim 1 where the electrodes at the bottom of the device are separated by reverse biased junctions.--

REMARKS

The list of references has been deleted. Missing reference number in Fig.2(a) has been added. Typographical error in the specification has been corrected. Claims 1, 3, 5-8, 10, 12 and 44 have been amended.

The Examiner objected to the listing of references in the application. The list of references has been deleted.